

第八章 p-n结

8.1 平衡p-n结特性

8.2 p-n结电流电压特性

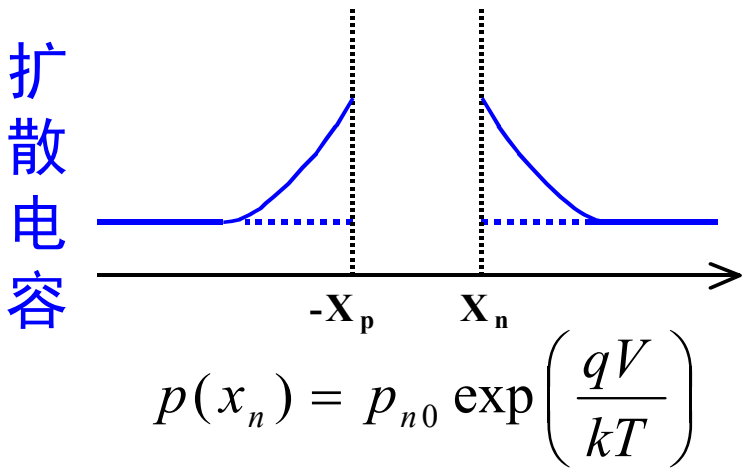
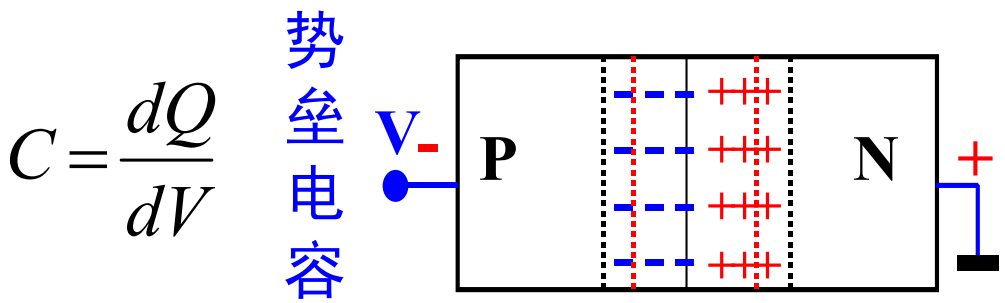
8.3 p-n结电容

8.4 p-n结的击穿

8.5 p-n结隧道效应

8.3 p-n结电容

8.3.1 势垒电容



—突变结

$$x_n = \frac{N_A}{N_A + N_D} X_D$$

$|Q| = AqN_Ax_p = AqN_Dx_n \longrightarrow |Q| = Aq \left[\frac{2\epsilon_0\epsilon_r}{q} \frac{N_A N_D}{N_A + N_D} (V_D - V) \right]^{1/2}$

耗尽层近似 $\rightarrow X_D = \sqrt{\frac{2\epsilon_r\epsilon_0(N_A + N_D)(V_D - V)}{qN_A N_D}}$

平行板电容

$$C_T = A \sqrt{\frac{q\epsilon_r\epsilon_0 N_B}{2(V_D - V)}}$$

突变结

$$\frac{A\epsilon_0\epsilon_r}{X_D} = C_T = \frac{dQ}{dV} = A \left[\frac{\epsilon_0\epsilon_r q}{2(V_D - V)} \frac{N_A N_D}{N_A + N_D} \right]^{1/2}$$

N_B : 轻掺杂浓度

8.3 p-n结电容₂

8.3.1 势垒电容

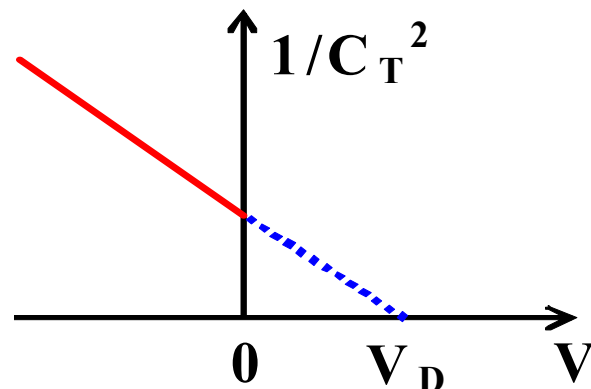
—突变结

$$C_T = A \sqrt{\frac{q\epsilon_r\epsilon_0 N_B}{2(V_D - V)}}$$

轻掺杂浓度

耗尽层近似

反向适用



—突变结（正向偏压）

$$C_T = \frac{dQ}{dV} = A \left[\frac{\epsilon_0\epsilon_r q}{2(V_D - V)} \frac{N_A N_D}{N_A + N_D} \right]^{1/2}$$

考虑势垒区中的载流子作用

$$C_T = 4C_T(0) = 4A \sqrt{\frac{\epsilon_r\epsilon_0 q N_A N_D}{2(N_A + N_D)V_D}}$$

8.3 p-n结电容₃

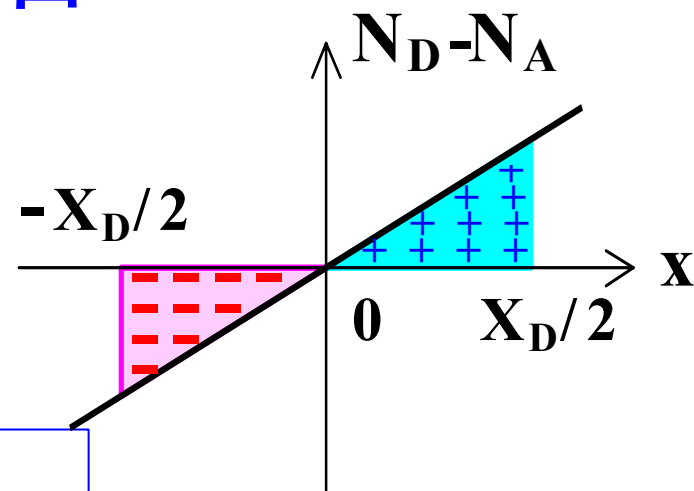
8.3.1 势垒电容

—线性缓变结

$$|Q| = A \int_0^{X_D/2} \rho(x) dx = A \int_0^{X_D/2} qa_j x dx = A \frac{qa_j X_D^2}{8}$$

$$X_D = \left(\frac{12 \varepsilon_r \varepsilon_0 (V_D - V)}{qa_j} \right)^{1/3}$$

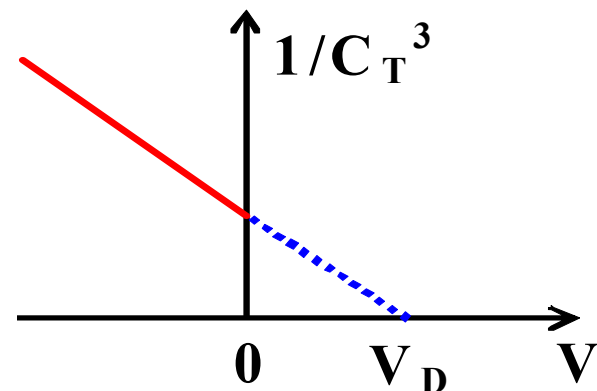
$$Q = A \left(\frac{9qa_j \varepsilon_r^2 \varepsilon_0^2}{32} \right)^{1/3} (V_D - V)^{2/3}$$



$$C_T = \frac{dQ}{dV} = A \left[\frac{qa_j \varepsilon_0^2 \varepsilon_r^2}{12(V_D - V)} \right]^{1/3}$$

$$= \frac{A \varepsilon_0 \varepsilon_r}{X_D}$$

平行板电容



8.3 p-n结电容₄

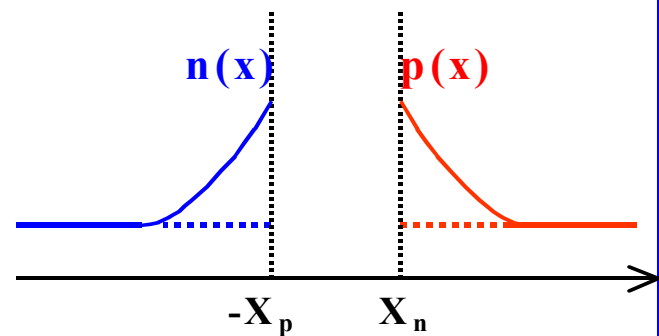
8.3.2 扩散电容 (正向偏压)

N区 $\Delta p(x) = p_{n0} \left[\exp\left(\frac{qV}{kT}\right) - 1 \right] \exp\left(-\frac{x - x_n}{L_p}\right)$

$$Q_p = Ae \int_{x_n}^{\infty} \Delta p(x) dx = AqL_p p_{n0} \left[\exp\left(\frac{qV}{kT}\right) - 1 \right]$$

$$C_{dp} = \frac{dQ_p}{dV} = A \frac{q^2 L_p p_{n0}}{kT} \exp\left(\frac{qV}{kT}\right)$$

P区 $C_{dn} = A \frac{q^2 L_n n_{p0}}{kT} \exp\left(\frac{qV}{kT}\right)$



总扩散电容 $Q = Q_p + Q_n$

$$\frac{dQ}{dV} = \frac{dQ_p}{dV} + \frac{dQ_n}{dV} \quad C_d = C_{dp} + C_{dn}$$

$$C_d = \left[Aq^2 \frac{(n_{p0}L_n + p_{n0}L_p)}{kT} \right] \exp\left(\frac{qV}{kT}\right)$$

大的正向偏压下，扩散电容为主

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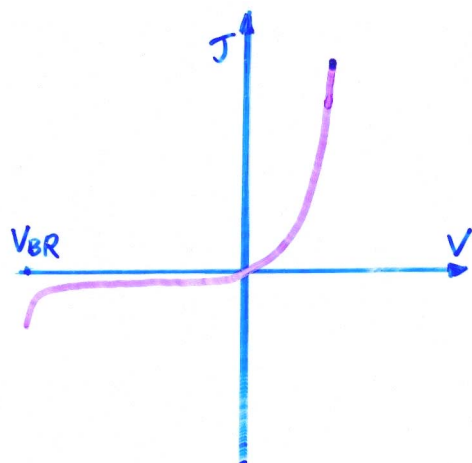
8.3 p-n结电容

8.4 p-n结的击穿

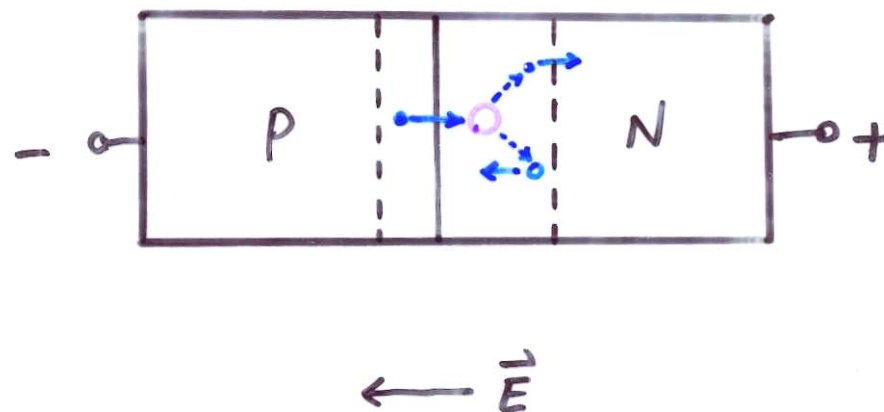
8.5 p-n结隧道效应

8.4 p-n结的击穿₁

8.4.1 雪崩击穿



碰撞离化率 α_n, α_p



— 一个载流子漂移单位距离内产生的电子-空穴对的数目

$$\alpha(E) = \alpha_0 \exp\left[-(E_0/E)^m\right]$$

雪崩击穿条件

$$N = \int_0^{x_D} \alpha_n dx = 1$$

倍增因子M

$$M = \frac{J}{J_0} = \frac{1}{1 - \int_0^{x_D} \alpha_n dx} \rightarrow \infty$$

8.4 p-n结的击穿₂

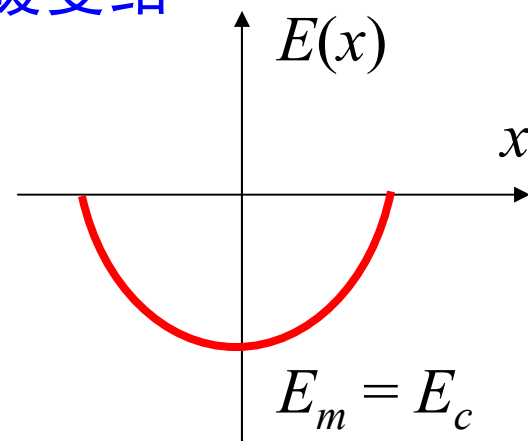
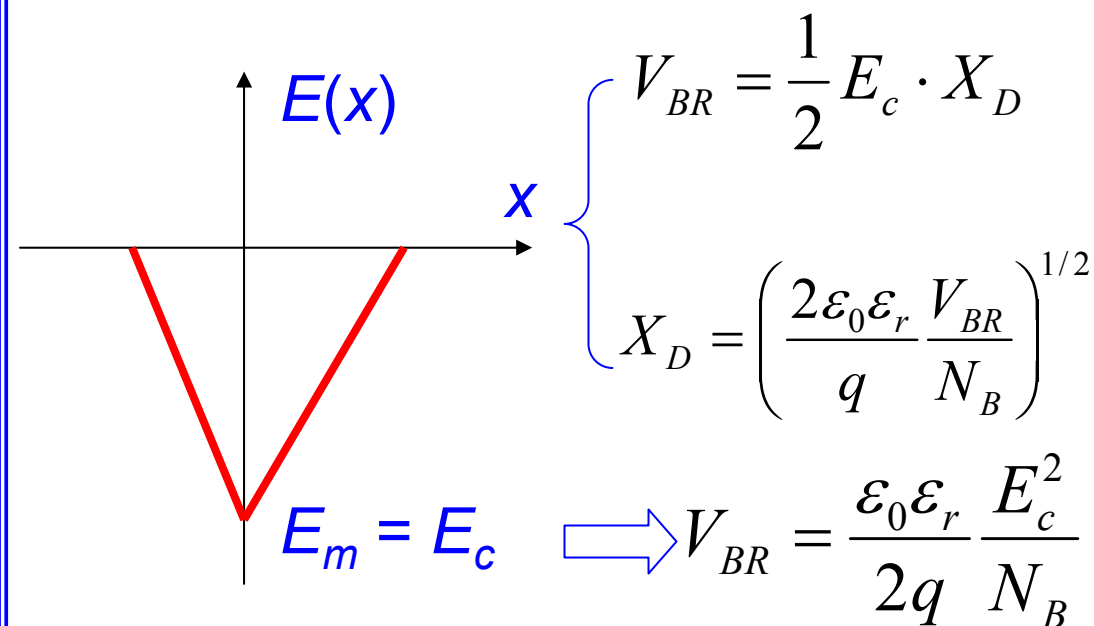
8.4.1 雪崩击穿

估算Si p-n结中的击穿电压 ($E_c = 2 \sim 5 \times 10^5$ V/cm)

$$X_D = \sqrt{\frac{2\epsilon_r\epsilon_0(N_A + N_D)(V_D - V)}{qN_A N_D}}$$

突变结

线性缓变结

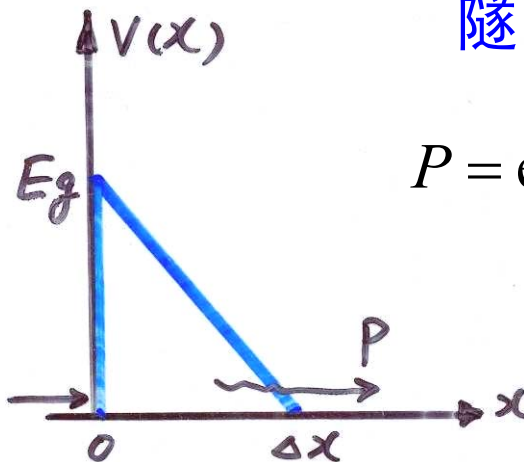
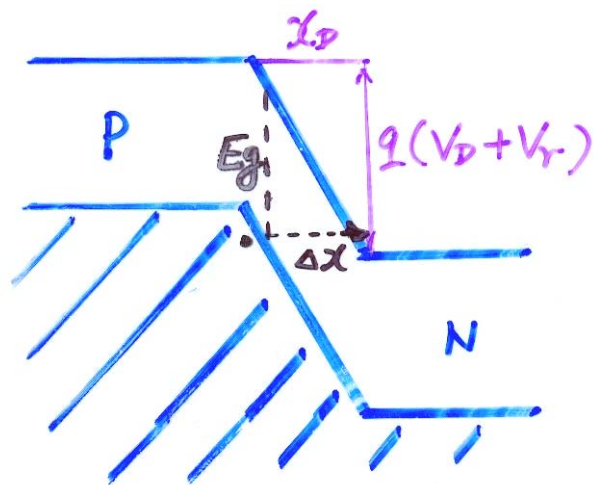


$$V_{BR} = \left(\frac{32\epsilon_0\epsilon_r E_c^3}{9\alpha_j q} \right)^{1/2}$$

$T \uparrow$ $I \downarrow$ $V_{BR} \uparrow$ 正温度系数

8.4 p-n结的击穿₃

8.4.2 齐纳击穿（隧道击穿）



隧穿几率

$$P = \exp \left[-\frac{8\pi}{3} \left(\frac{2m_n^*}{h^2} \right)^{1/2} E_g^{1/2} \Delta x \right]$$

$$\frac{E_g}{\Delta x} = \frac{q(V_D - V)}{x_D}$$

$$\Delta x = \frac{E_g}{q} \left(\frac{2\epsilon_0\epsilon_r}{q} \frac{1}{N_{eff}V_A} \right)^{1/2}$$

$$N_{eff} = \frac{N_D N_A}{N_D + N_A}$$

$$V_A = V_D - V$$

$T \uparrow$ $E_g \downarrow$ $P \uparrow$ $V_{BR} \downarrow$ 负温度系数

重掺杂Ge、Si p-n结

V_{BR}

$< 4E_g/q$
齐纳

$> 6E_g/q$
雪崩

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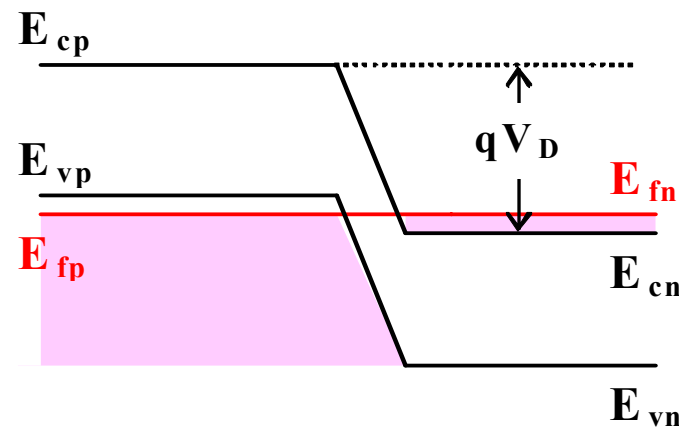
8.5 p-n结隧道效应₁

8.5.1 简并P-N结的能带图

简并半导体

$$P: E_{vp} > E_{fp}$$

$$N: E_{fn} > E_{cn}$$



简并P-N结

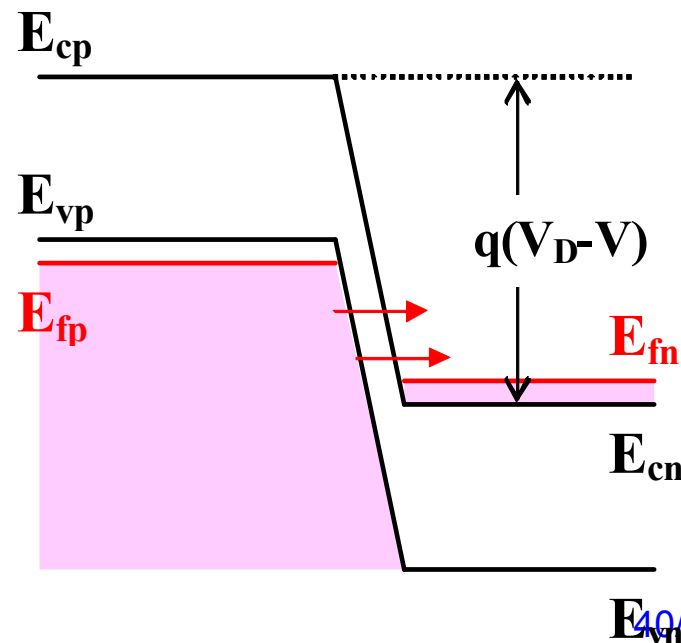
$$V = 0: E_{fp} = E_{fn} \quad V < 0: E_{fp} > E_{fn}$$

$$E_{vp} > E_{cn}$$

$$X_D = \sqrt{\frac{2\epsilon_r\epsilon_0(N_A + N_D)(V_D - V)}{qN_A N_D}}$$

$$N_D = N_A = 10^{21} \text{cm}^{-3}, V_D = 1.28 \text{eV}$$

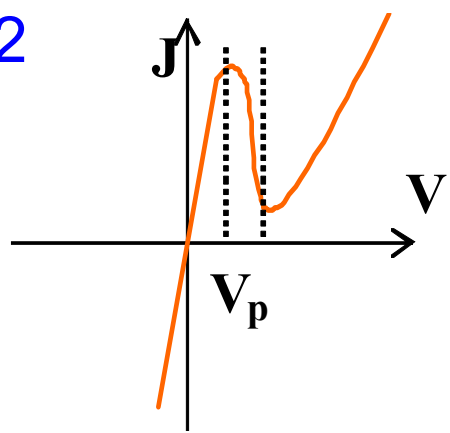
$$X_D = 0.53 \text{nm}$$



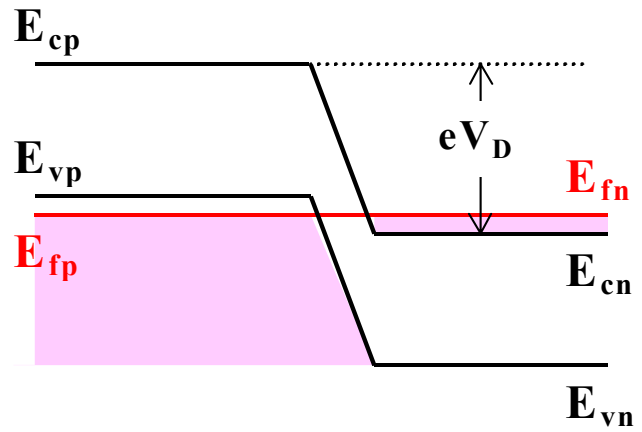
8.5 p-n结隧道效应₂

8.5.2 Esaki 二极管

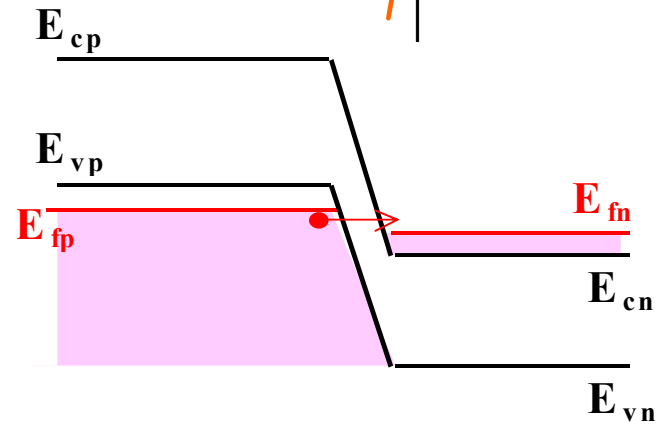
$V_p \sim 100-200\text{mV}$



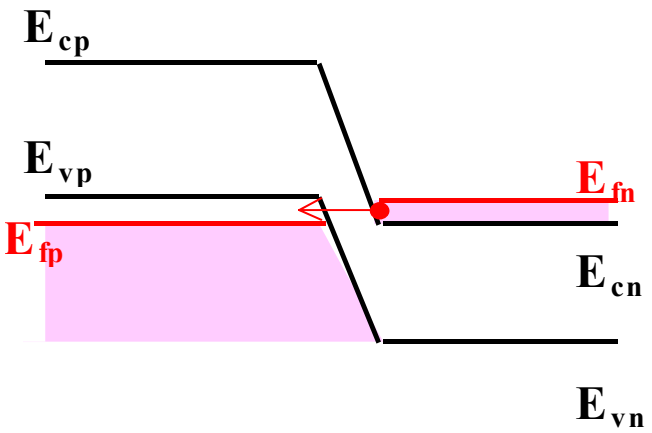
$V=0$



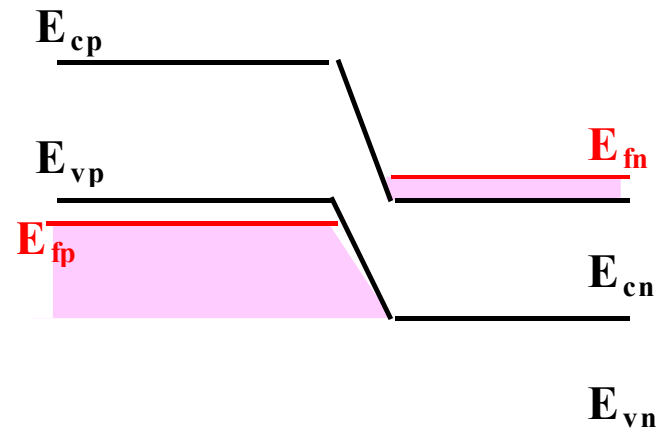
$V<0$



$V>0$



$V>0$



$V<V_p$

$V>V_p$